

DYNAMIC CHARACTERISTICS

APT77N60JC3

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C _{iss}	Input Capacitance	V _{GS} = 0V V _{DS} = 25V f = 1 MHz		13600		pF
C _{oss}	Output Capacitance			4400		
C _{rss}	Reverse Transfer Capacitance			290		
Q _g	Total Gate Charge ^③	V _{GS} = 10V V _{DD} = 300V I _D = 77A @ 25°C		505	640	nC
Q _{gs}	Gate-Source Charge			48		
Q _{gd}	Gate-Drain ("Miller") Charge			240		
t _{d(on)}	Turn-on Delay Time	RESISTIVE SWITCHING V _{GS} = 10V V _{DD} = 380V I _D = 77A @ 125°C R _G = 0.9Ω		18		ns
t _r	Rise Time			27		
t _{d(off)}	Turn-off Delay Time			110	165	
t _f	Fall Time			8	12	
E _{on}	Turn-on Switching Energy ^⑥	INDUCTIVE SWITCHING @ 25°C V _{DD} = 400V, V _{GS} = 15V I _D = 77A, R _G = 5Ω		1670		μJ
E _{off}	Turn-off Switching Energy			2880		
E _{on}	Turn-on Switching Energy ^⑥	INDUCTIVE SWITCHING @ 125°C V _{DD} = 400V, V _{GS} = 15V I _D = 77A, R _G = 5Ω		2300		
E _{off}	Turn-off Switching Energy			3100		

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
I _S	Continuous Source Current (Body Diode)			77	Amps
I _{SM}	Pulsed Source Current ^① (Body Diode)			231	
V _{SD}	Diode Forward Voltage ^② (V _{GS} = 0V, I _S = -77A)		1	1.2	Volts
t _{rr}	Reverse Recovery Time (I _S = -77A, di _S /dt = 100A/μs, V _R = 350V)		861		ns
Q _{rr}	Reverse Recovery Charge (I _S = -77A, di _S /dt = 100A/μs, V _R = 350V)		46		μC
dv _J /dt	Peak Diode Recovery dv _J /dt ^⑤			6	V/ns

THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
R _{θJC}	Junction to Case			0.22	°C/W
R _{θJA}	Junction to Ambient			40	

① Repetitive Rating: Pulse width limited by maximum junction temperature

② Pulse Test: Pulse width < 380 μs, Duty Cycle < 2%

③ See MIL-STD-750 Method 3471

④ Starting T_J = +25°C, L = 36.0mH, R_G = 25Ω, Peak I_L = 10A

⑤ dv_J/dt numbers reflect the limitations of the test circuit rather than the device itself. I_S ≤ -I_D 77A di_J/dt ≤ 700A/μs V_R ≤ V_{DSS} T_J ≤ 150°C

⑥ Eon includes diode reverse recovery. See figures 18, 20.

⑦ Repetitive avalanche causes additional power losses that can be calculated as P_{AV} = E_{AR} * f

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

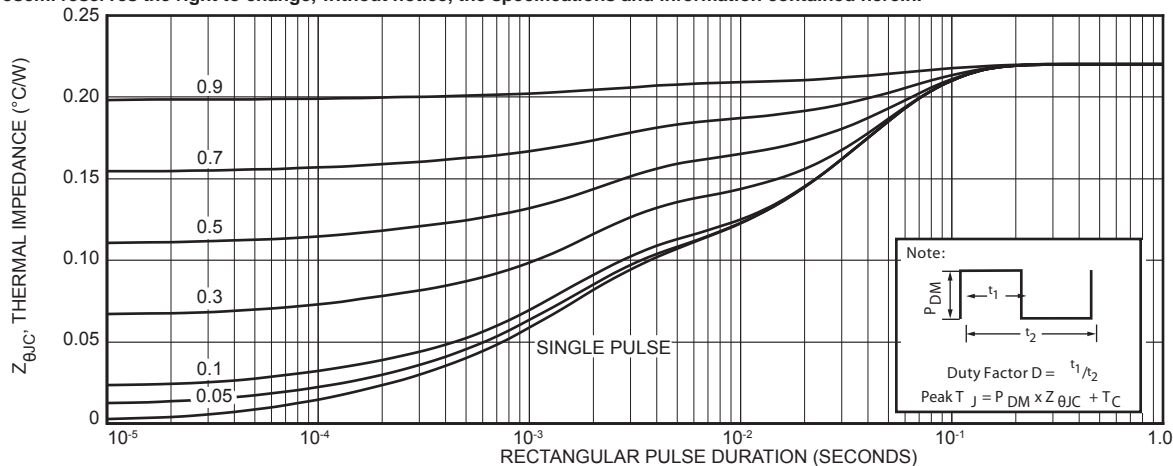


FIGURE 1, MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs PULSE DURATION

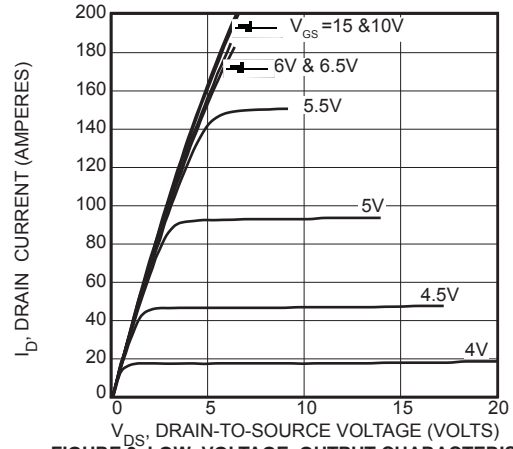


FIGURE 3, LOW VOLTAGE OUTPUT CHARACTERISTICS

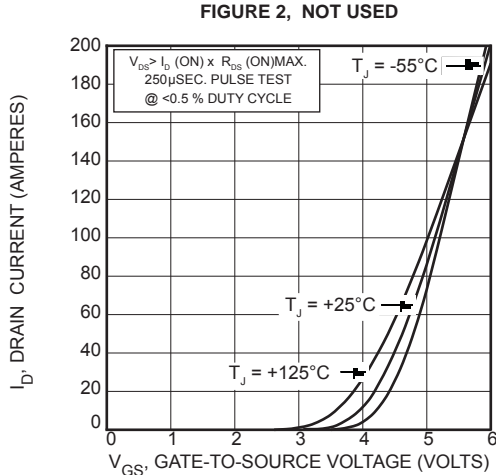


FIGURE 2, NOT USED

FIGURE 4, TRANSFER CHARACTERISTICS

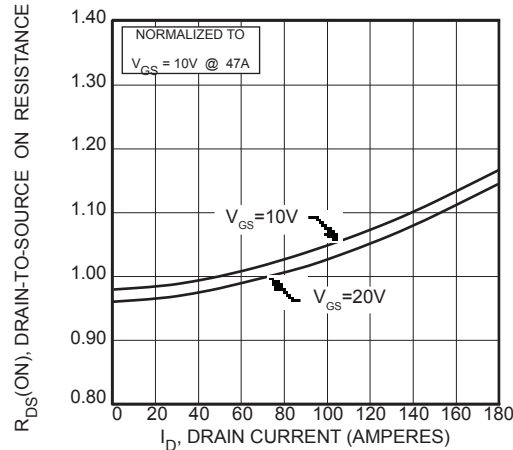


FIGURE 5, $R_{DS(ON)}$ vs DRAIN CURRENT

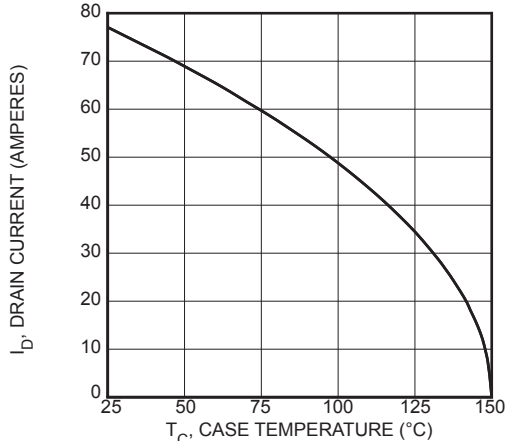


FIGURE 6, MAXIMUM DRAIN CURRENT vs CASE TEMPERATURE

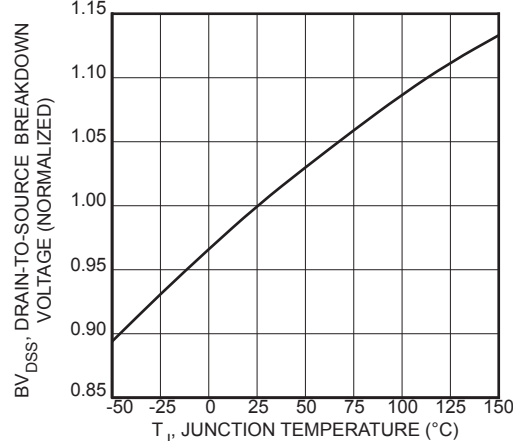


FIGURE 7, BREAKDOWN VOLTAGE vs TEMPERATURE

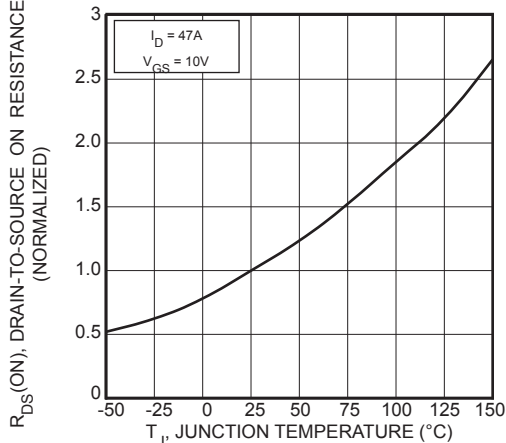


FIGURE 8, ON-RESISTANCE vs. TEMPERATURE

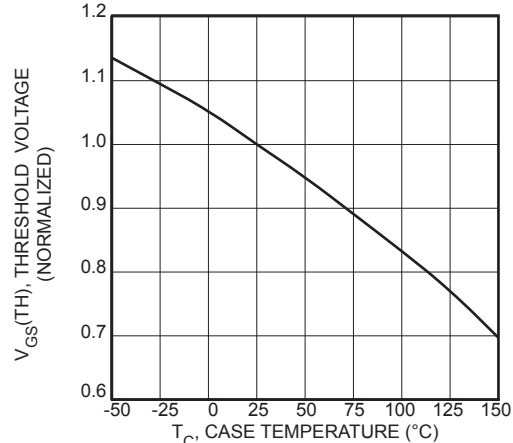


FIGURE 9, THRESHOLD VOLTAGE vs TEMPERATURE

Typical Performance

APT77N60JC3

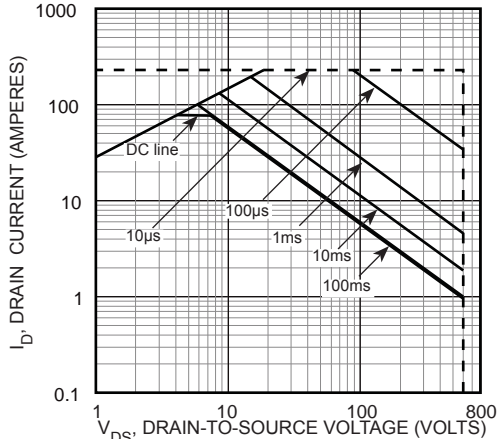


FIGURE 10, MAXIMUM SAFE OPERATING AREA

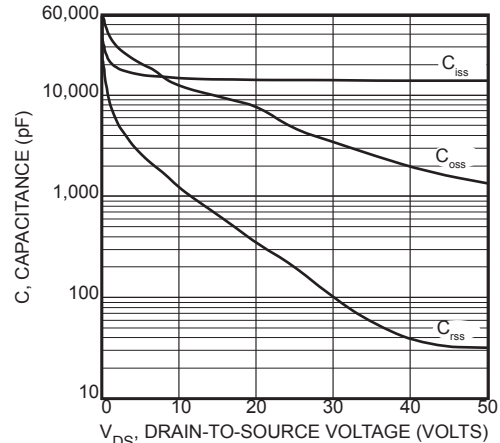


FIGURE 11, CAPACITANCE vs DRAIN-TO-SOURCE VOLTAGE

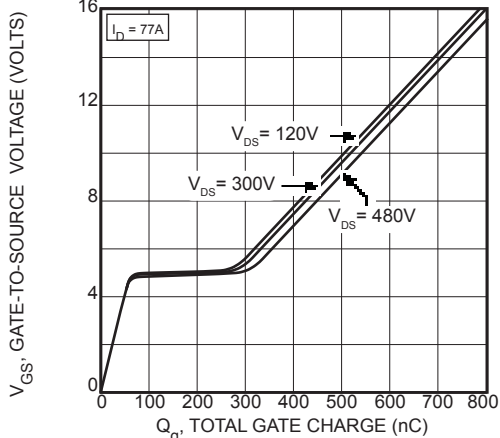


FIGURE 12, GATE CHARGES vs GATE-TO-SOURCE VOLTAGE

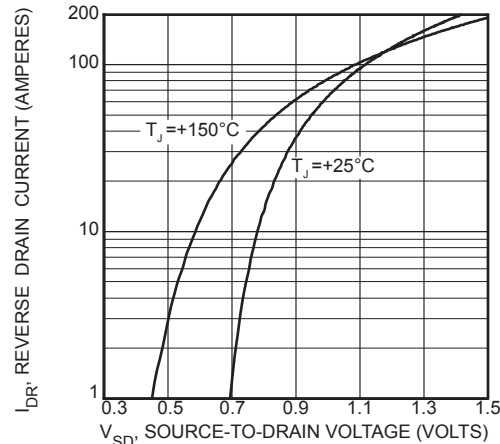


FIGURE 13, SOURCE-DRAIN DIODE FORWARD VOLTAGE

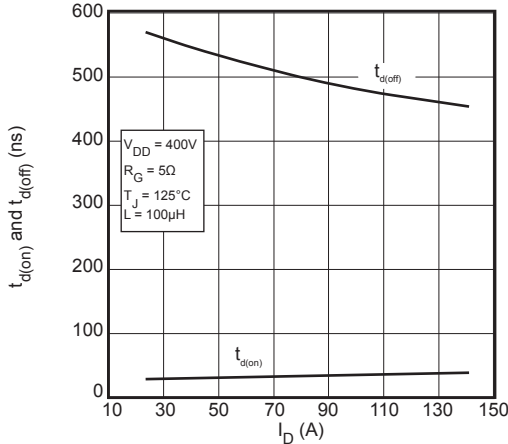


FIGURE 14, DELAY TIMES vs CURRENT

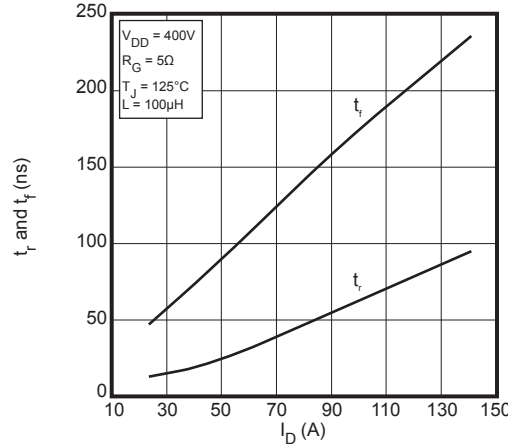


FIGURE 15, RISE AND FALL TIMES vs CURRENT

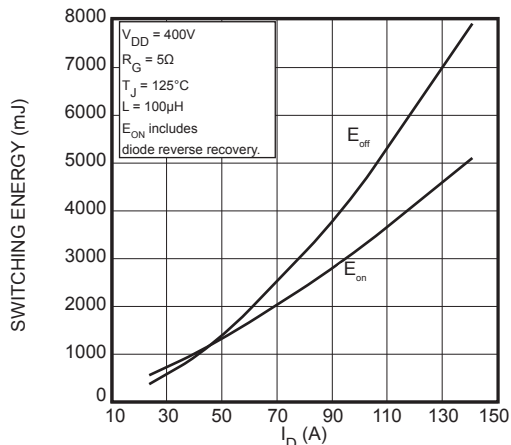


FIGURE 16, SWITCHING ENERGY vs CURRENT

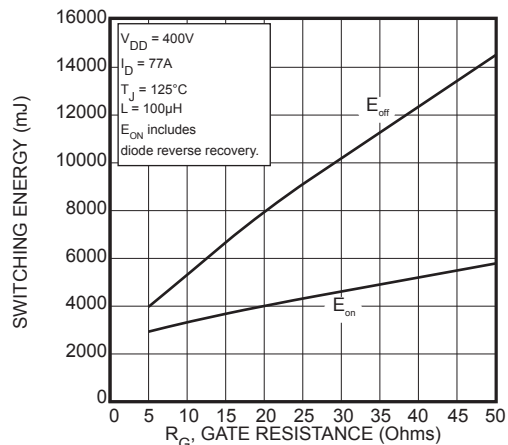


FIGURE 17, SWITCHING ENERGY vs. GATE RESISTANCE

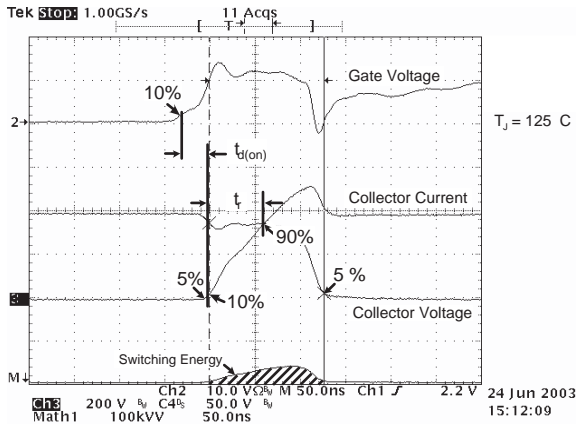


Figure 18, Turn-on Switching Waveforms and Definitions

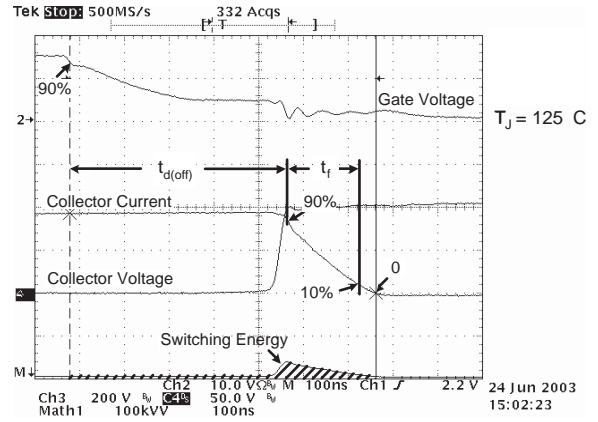


Figure 19, Turn-off Switching Waveforms and Definitions

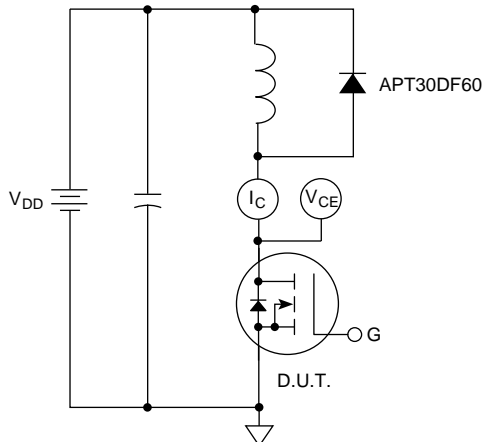
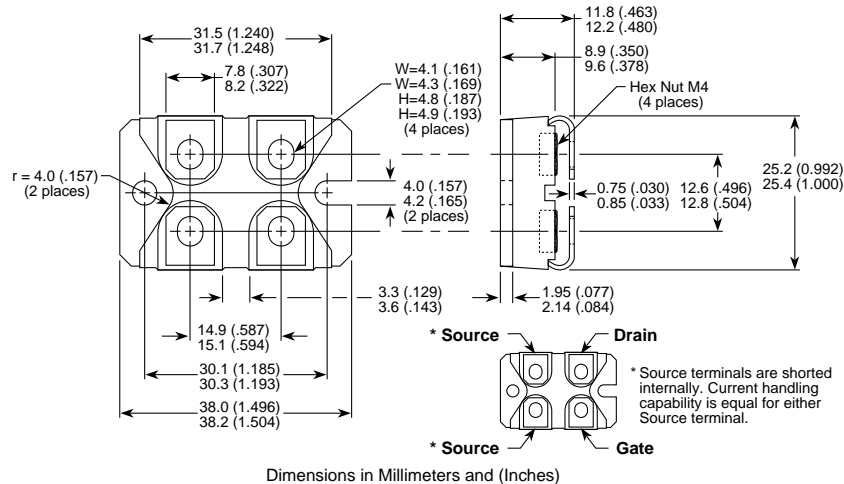


Figure 20, Inductive Switching Test Circuit

SOT-227 (ISOTOP®) Package Outline



Dimensions in Millimeters and (Inches)